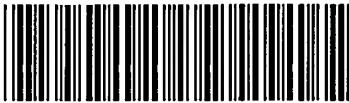


**Search Notes**

Application/Control No.

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Tan V. Mai

Applicant(s)/Patent under  
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Art Unit

2193

**SEARCHED**

Class	Subclass	Date	Examiner
708	552	9/15/2006	MAI

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	9/15/2006	MAI